

Search Notes

Application/Control No.

09/577,932

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

MARUYAMA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	797, 786, 737 & 738	3/6/2006	C.C.
438	14 - 18	3/6/2006	C.C.
438	401 & 460	3/6/2006	C.C.
438	460 - 465	3/6/2006	C.C.
438	613 - 617	3/6/2006	C.C.
228	180 & 22	3/6/2006	C.C.
257	E23.179	3/6/2006	C.C.
451	289 & 388	3/6/2006	C.C.
279	3	3/6/2006	C.C.
118	500 & 730	3/6/2006	C.C.
134	words	3/6/2006	C.C.
156	words	3/6/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
as same	as above	3/6/2006	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	3/6/2006	C.C.
Consulted with Sheila Clark	2/20/2002	C.C.
Consulted with David Graybill	4/27/2005	C.C.
Consulted with Daniel Howell 279/3; 118/500 & 730; classes 134 & 156	6/6/2005	C.C.
Consulted with Timothy Eley 451/289 & 388; 279/3	6/6/2005	C.C.